



#9/54. of time
②
3/26/03
J Bell

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : **Confirmation No. 6344**
Yoshio YANASE et al. : **Docket No. 2001-0615A**
Serial No. 09/856,982 : **Group Art Unit 2877**
Filed May 30, 2001 : **Examiner Sang H. Nguyen**

METHOD FOR INSPECTING SEMICONDUCTOR WAFER SURFACE

RECEIVED
MAR 21 2003
TIC 2800 MAIL ROOM

PETITION FOR EXTENSION OF TIME

Assistant Commissioner for Patents,
Washington, DC 20231

THE COMMISSIONER IS AUTHORIZED
TO CHARGE ANY DEFICIENCY IN THE
FEES FOR THIS PAPER TO DEPOSIT
ACCOUNT NO. 23-0975

Sir:

Petition hereby is made for a two month extension of time to respond to the communication of October 15, 2002.

The fee of \$410.00 is

- ☒ submitted herewith.
☐ to be charged to Deposit Account No. 23-0975. A duplicate copy of this Petition is enclosed.
- ☐ Small entity status of this application is established by a Small Entity Status Assertion which
☐ is enclosed.
☐ has been previously submitted.

Respectfully submitted,

Yoshio YANASE et al.

By

Joseph M. Gorski

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March 13, 2003